

Description

MLS65R380P, the silicon N-channel Enhanced MOSFETs, is obtained by advanced Super Junction technology which reduce the conduction loss, improve switching performance. The transistor is suitable device for SMPS, high speed switching and general purpose applications.

KEY CHARACTERISTICS

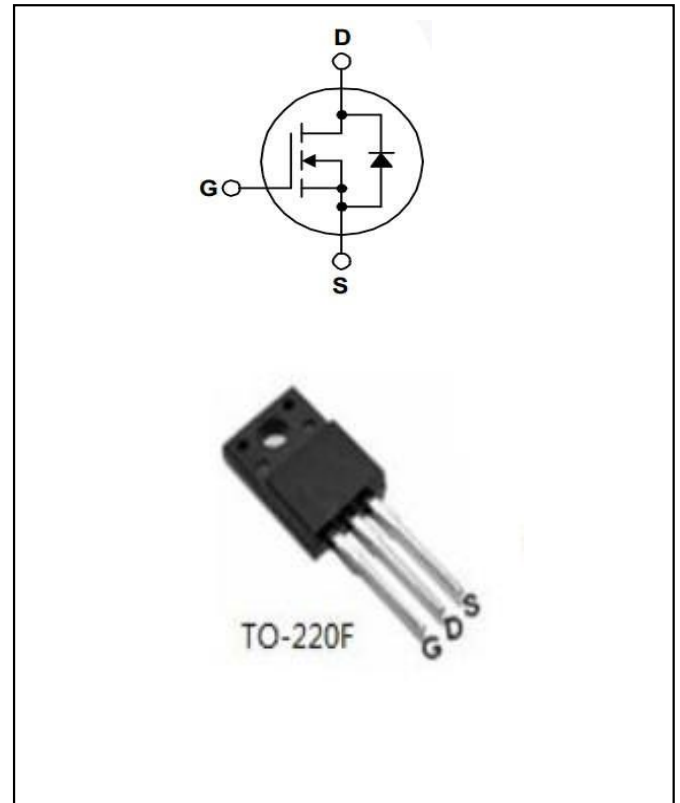
- ① $V_{DS}=650V, I_D=11A, R_{DS(ON)} < 0.33m\Omega @ V_{GS}=10V$

FEATURES

- ① Fast Switching
- ② 100% avalanche tested
- ③ Improved dv/dt capability

APPLICATIONS

- ① High frequency switching mode power supply



Package Marking And Ordering Information:

| Ordering Codes | Package | Product Code | Packing |
|----------------|---------|--------------|---------|
| MLS65R380P | TO-220F | M65R380P | Tube |

Electrical Characteristics @ Ta=25°C (unless otherwise specified)

Limited Parameters:

| Symbol | Parameter | Value | Units |
|-----------|---------------------------------------|-------|-------|
| V_{DSS} | Drain-to-Source Breakdown Voltage | 650 | V |
| I_D | Drain Current (continuous) at Tc=25°C | 11 | A |
| I_{DM} | Drain Current (pulsed) | 33 | A |
| V_{GS} | Gate to Source Voltage | ±20 | V |
| P_{tot} | Total Dissipation at Tc=25°C | 31 | W |
| T_j | Max. Operating Junction Temperature | 150 | °C |
| Eas | Single Pulse Avalanche Energy | 250 | mj |

Electrical Parameters:

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Unit |
|---------------------|--------------------------------------|--|----------------------|------|------|------|
| V _{DS} | Drain-source Voltage | V _{GS} =0V, I _D =250μA | 650 | | | V |
| R _{DS(on)} | Static Drain-to-Source on-Resistance | V _{GS} =10V, I _D =3.8A | | 0.33 | 0.38 | mΩ |
| V _{GS(th)} | Gated Threshold Voltage | V _{DS} =V _{GS} , I _D =250μA | 2 | | 4 | V |
| I _{DSS} | Drain-Source Leakage Current | V _{DS} =650V, V _{GS} =0V | | | 1.0 | μA |
| I _{GSS(F)} | Gate-Source Forward Leakage | V _{GS} =+30V | | | 100 | nA |
| I _{GSS(R)} | Gate-Source Reverse Leakage | V _{GS} =-30V | | | -100 | nA |
| C _{iss} | Input Capacitance | V _{GS} =0V V _{DS} =25 V _f =1.0MHz | | 770 | | pF |
| C _{oss} | Output Capacitance | | | 560 | | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 25 | | pF |
| Q _g | Total Gate Charge | | I _D =4.8A | | 21.8 | |
| Q _{gs} | Gate-Source Charge | V _{DD} =520V V _{GS} =10V | | 4.5 | | nC |
| Q _{gd} | Gate-Drain Charge | | | 8 | | nC |

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Unit |
|---------------------|---------------------|---|-----|-----|-----|------|
| t _{d(on)} | Turn-on Delay Time | I _D =4.8A V _{DD} =400V V _{GS} =10 V _{RG} =5Ω | | 11 | | nS |
| t _r | Turn-on Rise Time | | | 9 | | nS |
| t _{d(off)} | Turn-off Delay Time | | | 38 | | nS |
| t _f | Turn-off Fall Time | | | 8 | | nS |

| Source-Drain Diode Characteristics | | | | | | |
|------------------------------------|--|---|--------|------|------|-------|
| Symbol | Parameter | Test Conditions | Values | | | Units |
| | | | Min. | Typ. | Max. | |
| I _S | Continuous Source Current (Body Diode) | TC=25 °C | -- | -- | 11 | A |
| I _{SM} | Maximum Pulsed Current (Body Diode) | | -- | -- | 33 | A |
| V _{SD} | Diode Forward Voltage | I _S =4.8A, V _{GS} =0V(Note4) | -- | -- | 0.9 | V |
| T _{rr} | Reverse Recovery Time | I _S =4.8A, T _j =25°C dI _F /dt=100A/us, V _{GS} =0V | -- | 285 | -- | ns |
| Q _{rr} | Reverse Recovery Charge | | -- | 3135 | -- | nC |
| I _{rrm} | Reverse Recovery Current | | -- | 22 | -- | A |

Characteristics Curves

Figure 1a Safe Operating Area (No FullPAK)

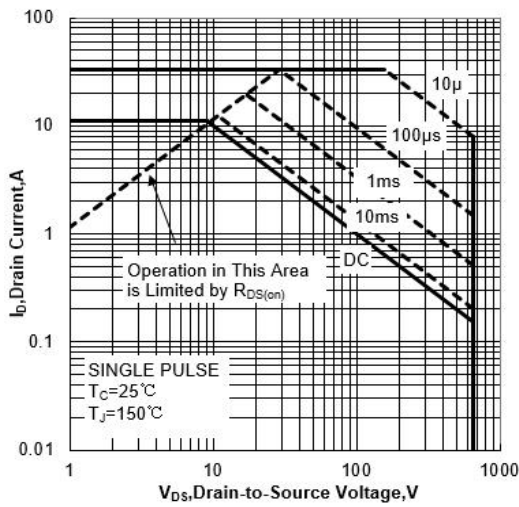


Figure 1b Safe Operating Area (FullPAK)

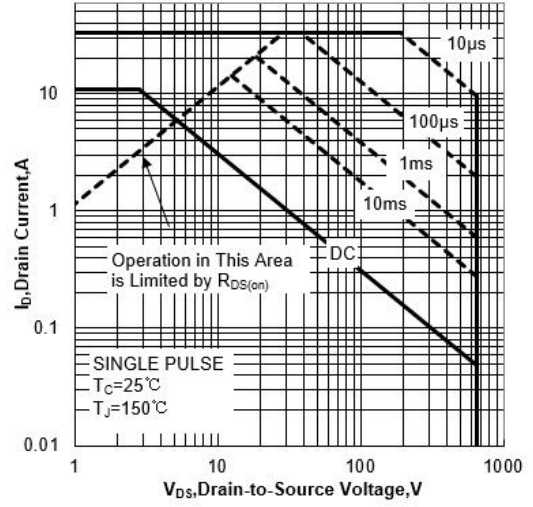


Figure 2a Power Dissipation (No FullPAK)

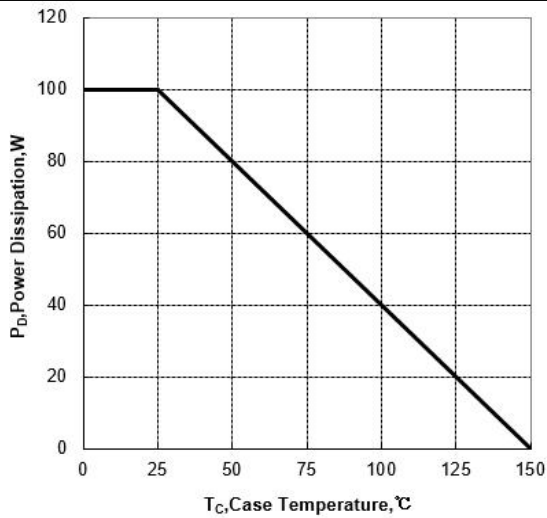


Figure 2b Power Dissipation (FullPAK)

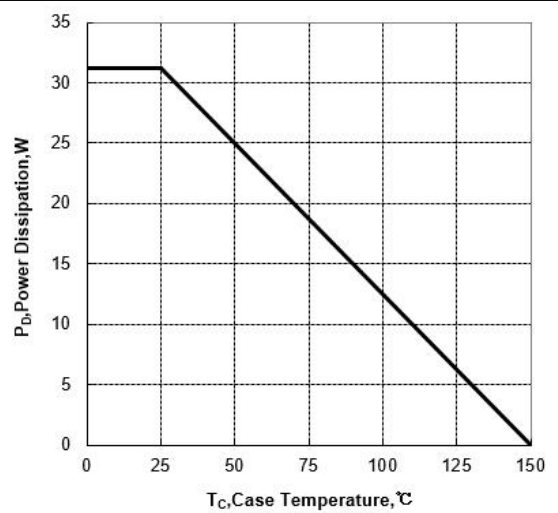


Figure 6 Typical Drain to Source ON Resistance vs Drain Current

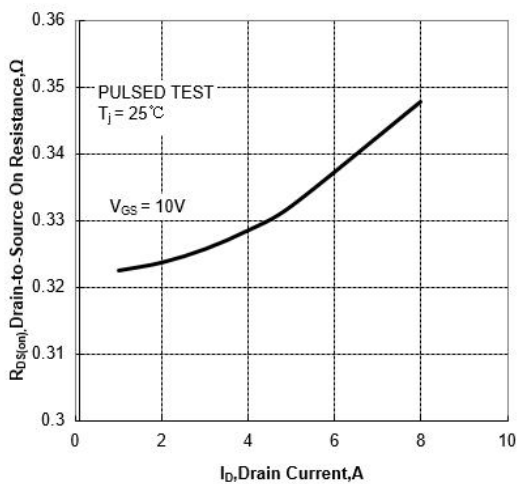


Figure 7 Typical Drain to Source on Resistance vs Junction Temperature

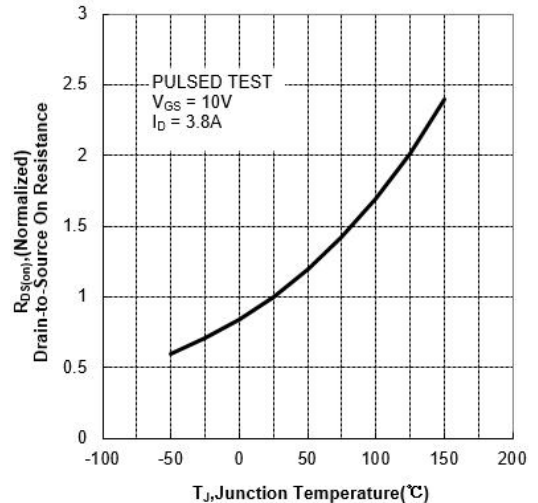


Figure 8 Typical Theshold Voltage vs Junction Temperature

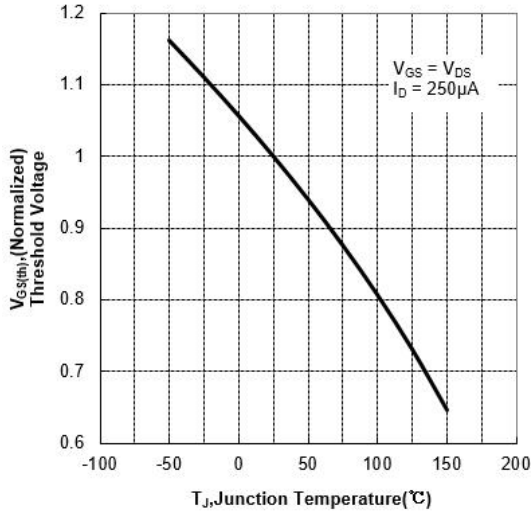


Figure 9 Typical Breakdown Voltage vs Junction Temperature

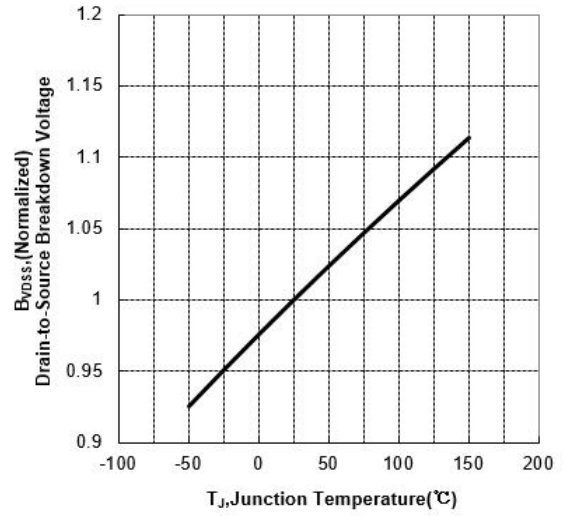


Figure 10 Typical Theshold Voltage vs Junction Temperature

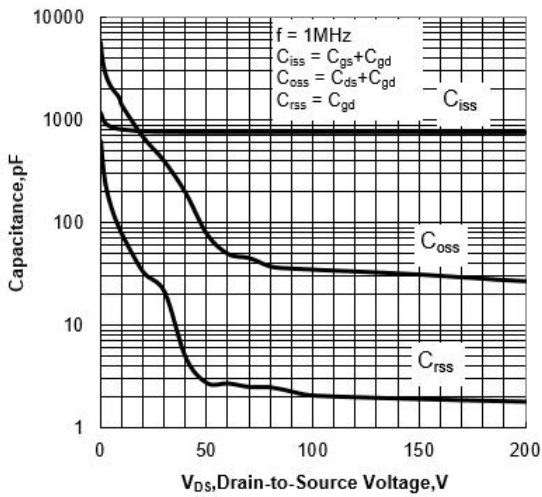
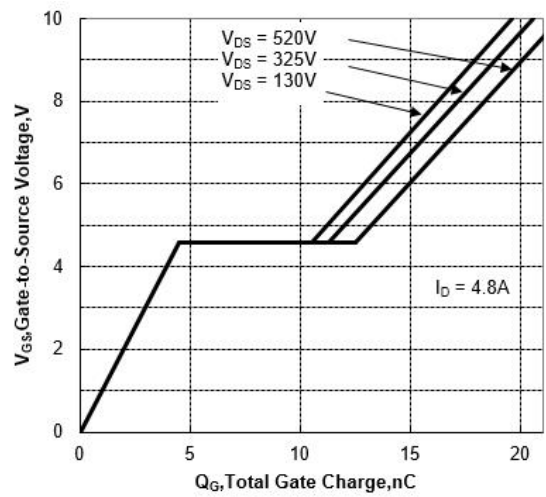


Figure 11 Typical Breakdown Voltage vs Junction Temperature



Test Circuit and Waveform

Figure 12 Gate Charge Test Circuit

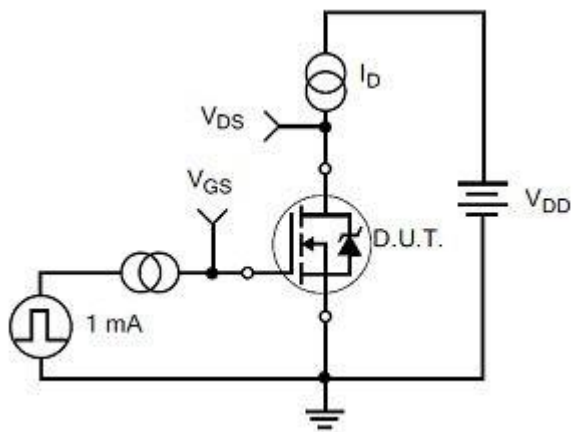


Figure 13 Gate Charge Waveforms

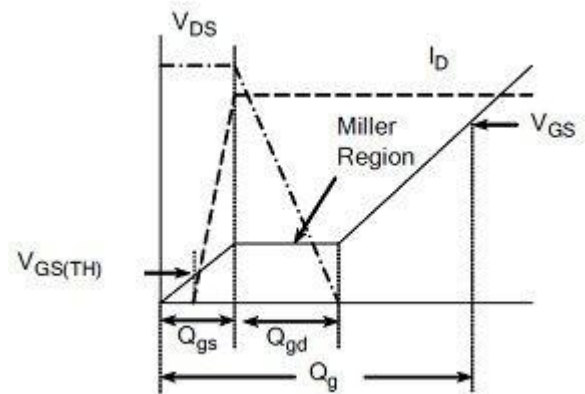


Figure 14 Resistive Switching Test Circuit

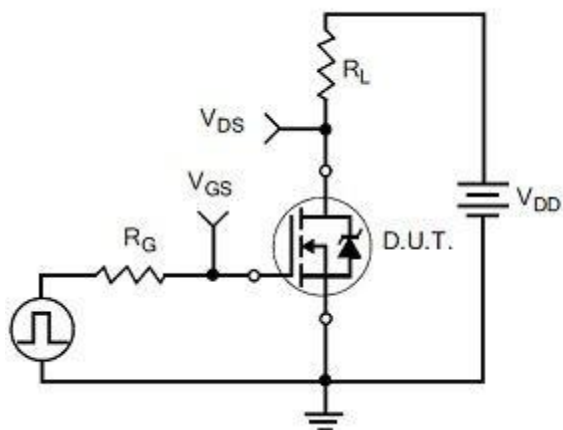


Figure 15 Resistive Switching Waveforms

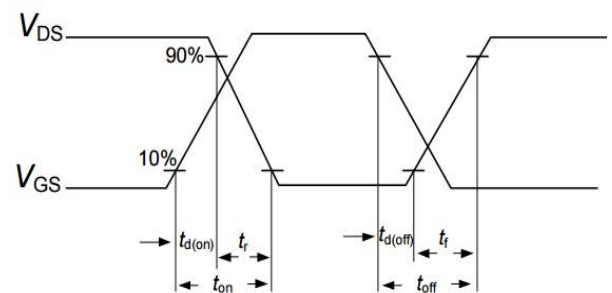


Figure 16 Diode Reverse Recovery Test Circuit

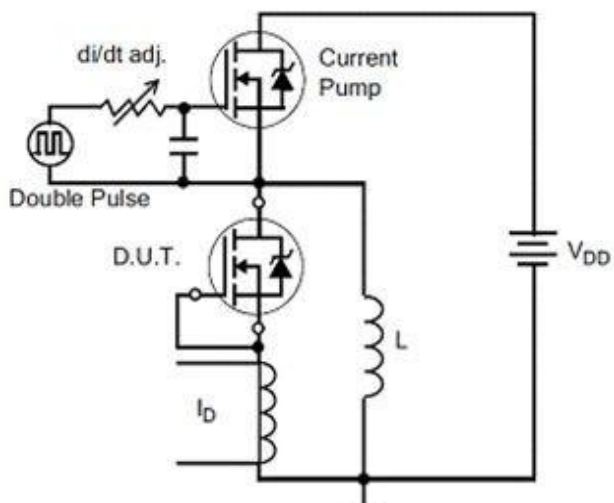


Figure 17 Diode Reverse Recovery Waveform

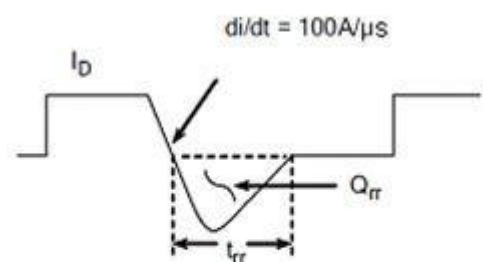


Figure 18 Unclamped Inductive Switching Test Circuit

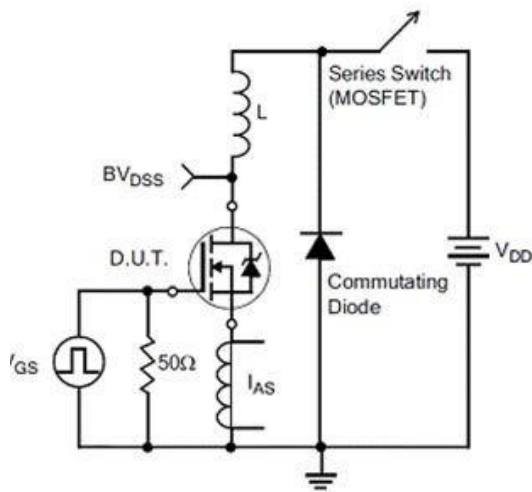
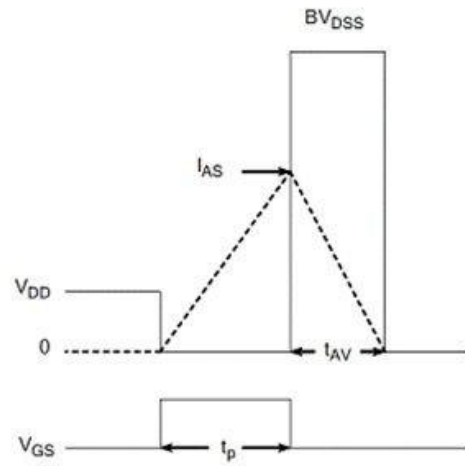
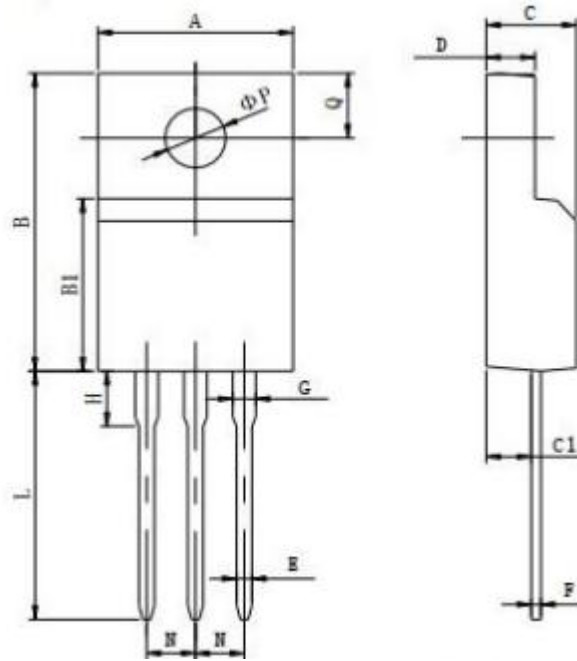


Figure 19 Unclamped Inductive Switching Waveform



Package Description



| Items | Values(mm) | |
|-------|------------|------|
| | MIN | MAX |
| A | 9.60 | 10.4 |
| B | 15.4 | 16.2 |
| B1 | 8.90 | 9.50 |
| C | 4.30 | 4.90 |
| C1 | 2.10 | 3.00 |
| D | 2.40 | 3.00 |
| E | 0.60 | 1.00 |
| F | 0.30 | 0.60 |
| G | 1.12 | 1.42 |
| H | 3.40 | 3.80 |
| | 1.60 | 2.90 |
| L | 12.0 | 14.0 |
| N | 2.34 | 2.74 |
| Q | 3.15 | 3.55 |
| φp | 2.90 | 3.30 |

TO-220F Package



NOTE:

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. MOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. Shenzhen Minos reserves the right to make changes in this specification sheet and is subject to change without prior notice.

CONTACT:

深圳市迈诺斯科技有限公司（总部）

地址：深圳市福田区华富街道田面社区深南中路4026号田面城市大厦22B-22C

邮编：518025

电话：0755-83273777